

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/810,445	LEHE ET AL.	•	
Examiner	Art Unit		
Victor X. Nguyen	3734		

	SEAR	CHED	
Class	Subclass	Date	Examiner
606	159,191	10/5/2007	VN
	198,200	ij	"
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventors searched	10/5/2007	VN		
Text/East searched	"	".		
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